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Base on Multi-Level software structure for Efuse Common Library

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ADVANTEST



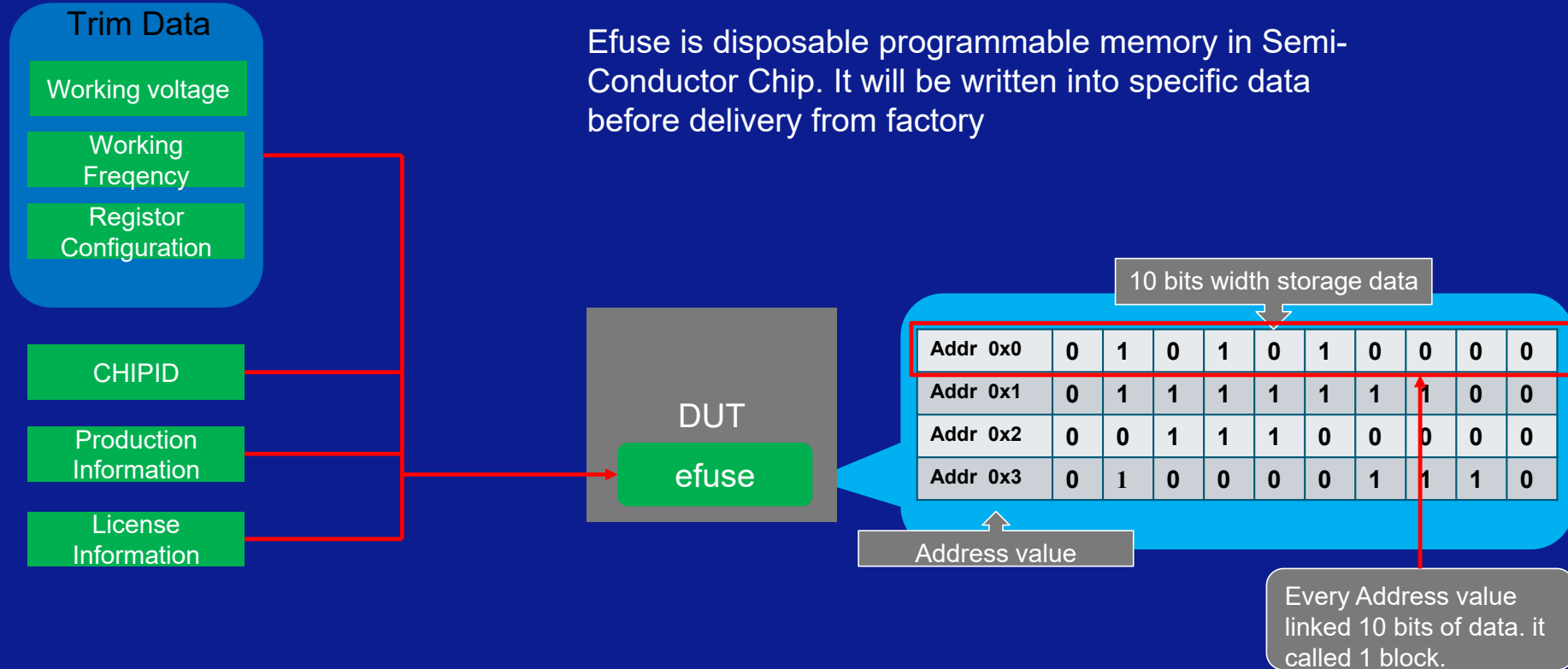
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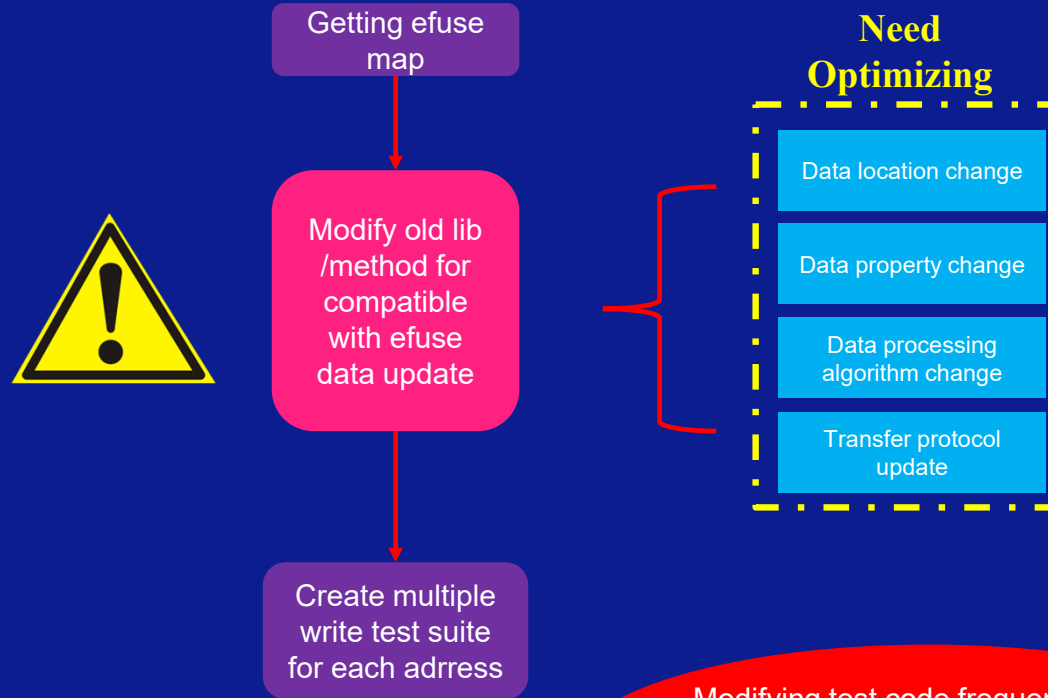
Agenda

- What is Efuse
- Normal Processing Flow For efuse
- New efuse Structure

What Is efuse



Normal Processing Flow For efuse



Originally efuse test will running as below:

Firstly, collecting data distribution information from chip introduction document(efuse map).

Secondly, **developing test method for transfer real data into efuse data container.**

Finally, **download efuse data into chip using specific protocol.**

Based on these steps, testing engineer will refactor test code of efuse data management.

Modifying test code frequently will influence stability and robust of test program, and it will increase the risk of error occurring of test code.

Data location change

Normal Processing Flow For efuse

address	Byte0	Byte1	Byte2	Byte3	Byte4	Byte5	Byte6	Byte7	Byte8	Byte9
0x0	Data1	Data2		Chip Version				Reserve Data		
0x1	Calibration data									
0x2	ChipID				Processing Log Data			Reserve Data		

Address 0x0 = (Chip Version >> 24) | (Data2 >> 8) | (Data1 >> 0)

Address 0x1 = Calibration data

Address 0x2 = (Processing Log Data >> 32) | (ChipID)

address	Byte0	Byte1	Byte2	Byte3	Byte4	Byte5	Byte6	Byte7	Byte8	Byte9
0x0	Data2		Data1		Reserve Data			Chip Version		
0x1	Processing Log Data				Reserve Data					
0x2	Calibration data				Reserve Data					

Switch data position in same address

Switch data position in same address

Switch data position in different address

Address 0x0 = (Chip Version >> 48) | (Data2 >> 0) | (Data1 >> 16)

Address 0x1 = (Processing Log Data >> 32) | (ChipID)

Address 0x2 = Calibration data

Lot of code change

Data Shift

Data region reflect

Code

To remap Data location in efuse address structure, we need do lot of work for data shift and data region reflect. This structure is unfriendly with program update if data location has change, and every change action will lead to big potential risk

Data property change

Normal Processing Flow For efuse

address	Byte0	Byte1	Byte2	Byte3	Byte4	Byte5	Byte6	Byte7	Byte8	Byte9
0x0	Data1	Data2		Chip Version				Reserve Data		
0x1	Calibration data									
0x2	ChipID				Processing Log Data			Reserve Data		

Address 0x0 = (Chip Version >> 24) | (Data2 >> 8) | (Data1 >> 0)
 Address 0x1 = Calibration data
 Address 0x2 = (Processing Log Data >> 32) | (ChipID)

Same code statement in **different** efuse data.
 If we send 32 bits data into Chip Version, byte6 will be written into **invalid data**

Chip Version data length -1

address	Byte0	Byte1	Byte2	Byte3	Byte4	Byte5	Byte6	Byte7	Byte8	Byte9
0x0	Data 1	Data2		Chip Version				Reserve Data		
0x1	Calibration data									
0x2	ChipID				Processing Log Data			Reserve Data		

Data property change

Normal Processing Flow For efuse

address	Byte0	Byte1	Byte2	Byte3	Byte4	Byte5	Byte6	Byte7	Byte8	Byte9
0x0	Data1	Data2		Chip Version				Reserve Data		
0x1	Calibration data									
0x2	ChipID				Processing Log Data				Reserve Data	

Tough Point

Chip Version = Chip Version & 0xffffffff

Chip Version = Chip Version & 0xffff

Address 0x0 = (Chip Version >> 24) | (Data2 >> 8) | (Data1 >> 0)

Address 0x1 = Calibration data

Address 0x2 = (Processing Log Data >> 32) | (ChipID)

Addition code

For prevent invalid data write into byte6, we need add bit mask for ensuring data length is correct before data shift.

But this changing need insert each position that data length is different

Chip Version data length - 1

Data length change

Code



Lot of code working

address	Byte0	Byte1	Byte2	Byte3	Byte4	Byte5	Byte6	Byte7	Byte8	Byte9
0x0	Data 1	Data2		Chip Version				Reserve Data		
0x1	Calibration data									
0x2	ChipID				Processing Log Data			Reserve Data		

Data property change

Normal Processing Flow For efuse

address	Byte0	Byte1	Byte2	Byte3	Byte4	Byte5	Byte6	Byte7	Byte8	Byte9
0x0	Data 1	Data2		Chip Version			Reserve Data			

If Chip version data has 2 sub-data: data1 and data2

Each of these data is calculated in different links, so it cannot get value at same time

For data1, we need calculate address data as below:

Chip version = $((data1 \& 0x3ff) | ((data1 \& 0x7c00) \gg 14)) \& 0x07c3ff$ Address0x0 = Address0x0 | Chip version >> 24

For data2, we need calculate address data as below:

Chip version = $((data2 \& 0xf) \gg 10) | ((data2 \& 0x1f0) \gg 19)) \& 0xf83c00$ Address0x0 = Address0x0 | Chip version >> 24

Bit 0	Bit 1	Bit 2	Bit 3	Bit 4	Bit 5	Bit 6	Bit 7	Bit 8	Bit 9	Bit 10	Bit 11	Bit 12	Bit 13	Bit 14	Bit 15	Bit 16	Bit 17	Bit 18	Bit 19	Bit 20	Bit 21	Bit 22	Bit 23
dat a1	dat a1	dat a1	dat a1	dat a1	dat a1	dat a1	dat a1	dat a1	dat a1	dat a2	dat a2	dat a2	dat a2	dat a1	dat a1	dat a1	dat a1	dat a1	dat a2	dat a2	dat a2	dat a2	dat a2

If data bit location has changed, the reference calculate formula will changed accordingly

For data1, we need calculate address data as below:

Chip version = $((data1 \& 0xff) | ((data1 \& 0x7f00) \gg 14)) \& 0x1fc0ff$

For data2, we need calculate address data as below:

Chip version = $((data2 \& 0x3f) \gg 8) | ((data2 \& 0x1e0) \gg 21)) \& 0xe03f00$

Bit 0	Bit 1	Bit 2	Bit 3	Bit 4	Bit 5	Bit 6	Bit 7	Bit 8	Bit 9	Bit 10	Bit 11	Bit 12	Bit 13	Bit 14	Bit 15	Bit 16	Bit 17	Bit 18	Bit 19	Bit 20	Bit 21	Bit 22	Bit 23
dat a1	dat a1	dat a1	dat a1	dat a1	dat a1	dat a1	dat a1	dat a2	dat a2	dat a2	dat a2	dat a2	dat a2	dat a1	dat a1	dat a1	dat a1	dat a1	dat a1	dat a1	dat a2	dat a2	dat a2

Impact: Lot of complex data calculate formula need change, and counter-intuitive mask process will **greatly amplify probability of risk occurrence.**

Assign value format change

Code



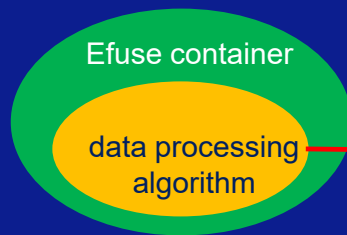
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Data processing
algorithm change

Normal Processing Flow For efuse

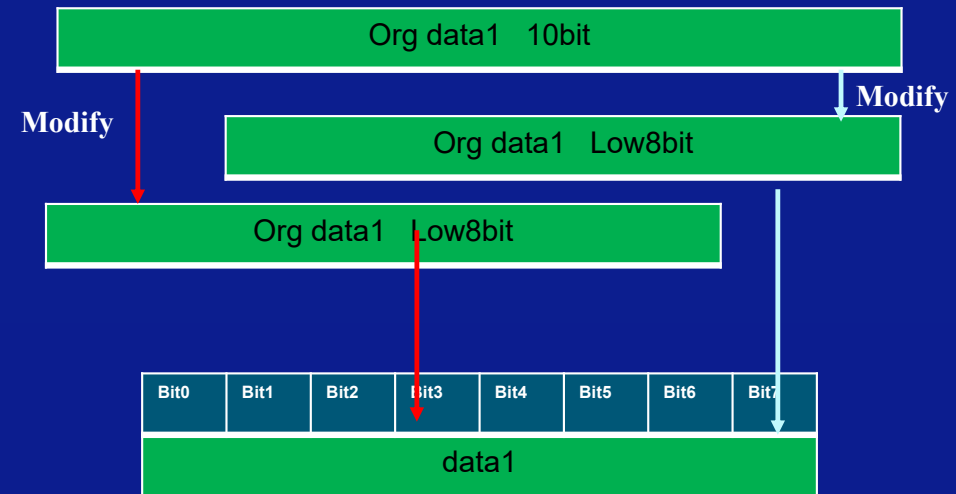
address	Byte0	Byte1	Byte2	Byte3	Byte4	Byte5	Byte6	Byte7	Byte8	Byte9
0x0	Data 1	Data2		Chip Version			Reserve Data			



Cannot modifying data
processing algorithm skip
Efuse container structure

Normal data processing algorithm code often mix into data container structure code, this structure has several problem below:

1. **it is hard to update algorithm without influence data structure code.**
2. **It is hard to find out update code position for new member**



Transfer protocol
update

Normal Processing Flow For efuse

Problem 1:

Protocol update always need
modify protocol structure
reference code like:
Write Action
Read Action
Waite Action

Problem 2:

we need develop different
program for different die

Problem 1:

Efuse Data



Protocol A



Efuse Data

Protocol B



Write
Read
wait

Lot of code
refactor work

Write
Read
wait

Problem 2:

Efuse Data 1

Protocol A



DieA

Efuse Data 2

Protocol B

DieB

Program A

Protocol
A

Program B

Protocol
B

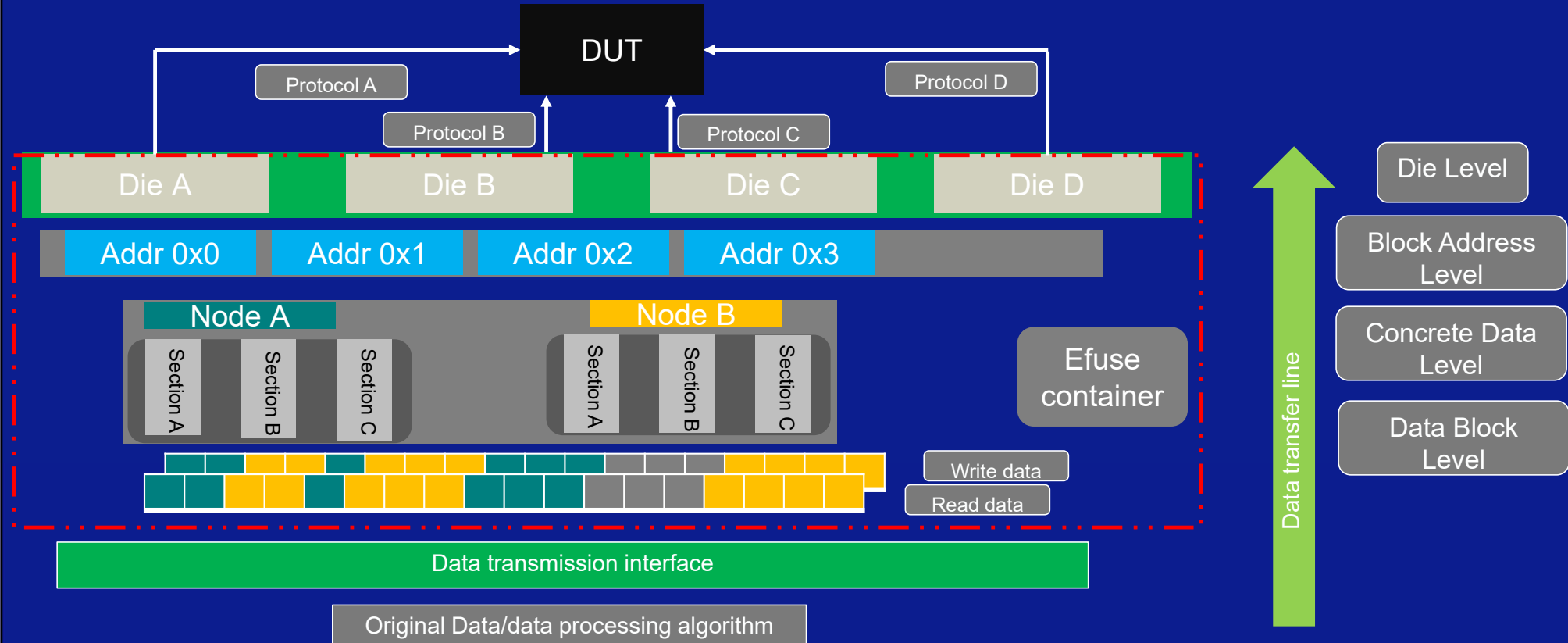
Different Protocol in different
program

New efuse Structure

Normal Process	New Efuse Solution
Data location change	CSV Input Format
Data property change	CSV Input Format/ Data transmission interface
Data processing algorithm change	Data transmission interface
Transfer protocol update	Multi-Die Protocol Management/Protocol data filling

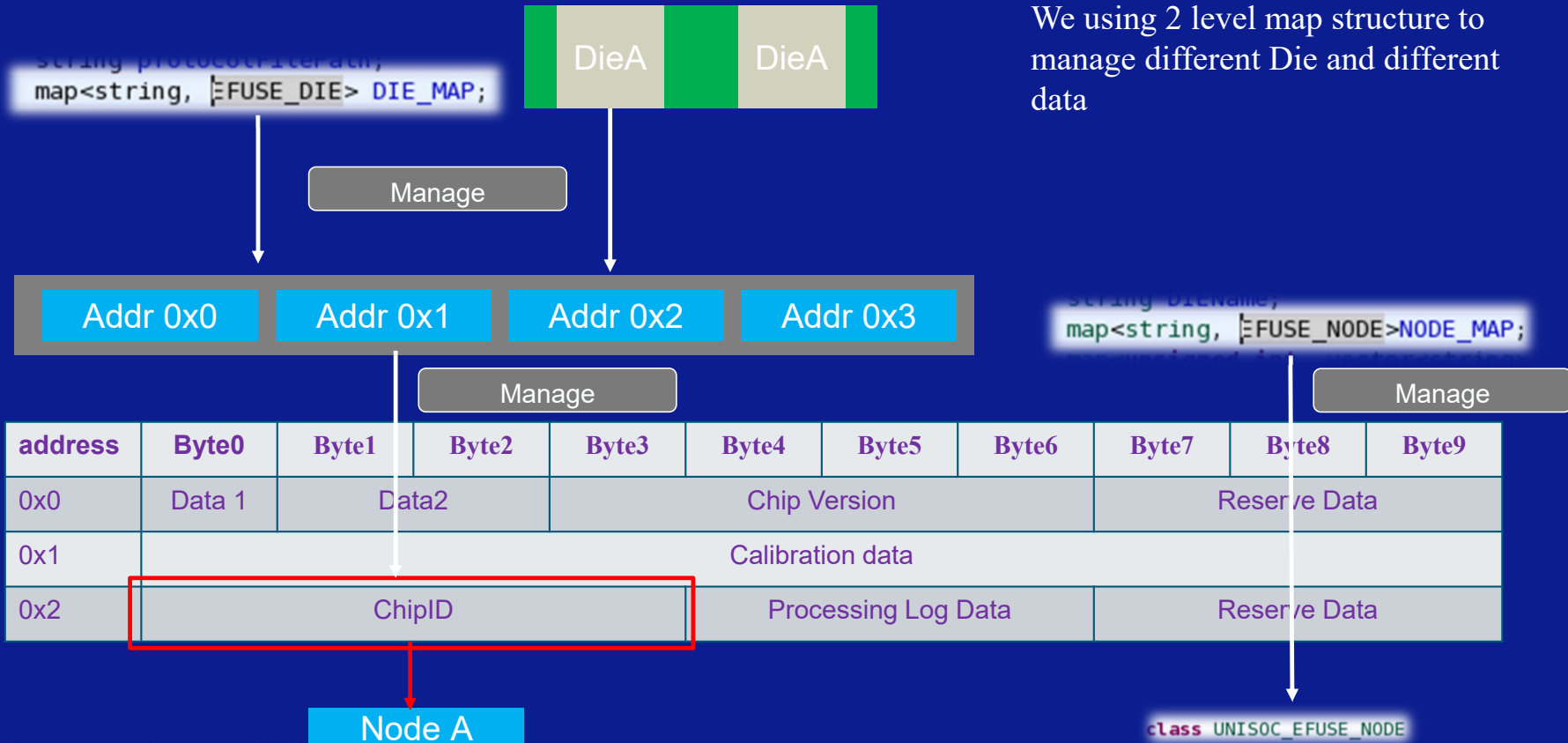
New efuse Structure

- Multi-Level Data Container



New efuse Structure

- Multi-Level Data Container



We using 2 level map structure to manage different Die and different data

New efuse Structure

- CSV Input Format

address	Byte0	Byte1	Byte2	Byte3	Byte4	Byte5	Byte6	Byte7	Byte8	Byte9
0x0	Data 1	Data2		Chip Version				Reserve Data		
0x1	Calibration data									
0x2	ChipID				Processing Log Data			Reserve Data		

Address 0x0 = (Chip Version >> 24) | (Data2 >> 8) | (Data1 >> 0)
 Address 0x1 = Calibration data
 Address 0x2 = (Processing Log Data >> 32) | (ChipID)

Chip Version = Chip Version & 0xffffffff
 Chip Version = Chip Version & 0xfffff

Coding work



	NodeName	HDMI_TRIM	CVBS_TRIM	dsv
1	signBit	Y	N	Y
2	BlockID	0	3	4
3	BlockLoc	0,5,7~10,15,20	0~23	0,7~8
4	Type	WR	WR	WR

All above coding work become
 simple forms input
 Efficiency and safety improve
 greatly



Data Shift

Data region
reflect

Data length
change

All these action only
 need modify CSV
 data

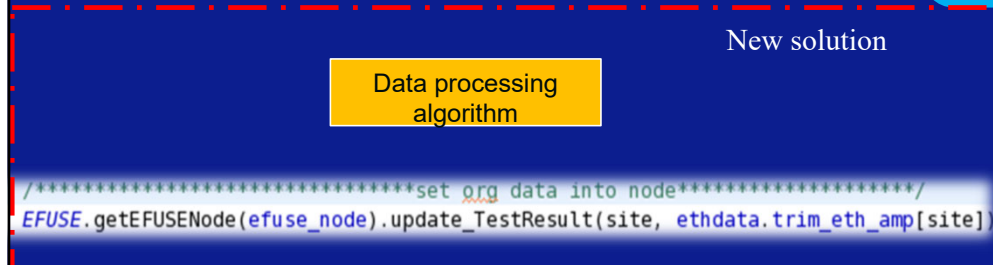
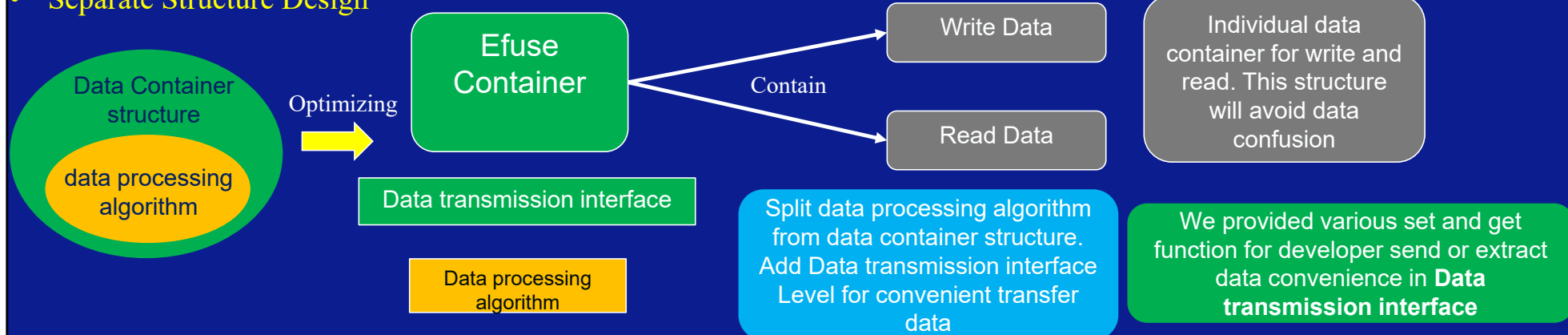


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New efuse Structure

- Separate Structure Design



We using set/get function at where original data is generate or calculate, this make program updating become easy

```
void update_TestResult(int site, int data);
void update_TestResult(int site, int data, int BitLoc);
void update_TestResult(int site, Unsigned128 data);
void update_TestResult(int site, Unsigned128 data, Unsigned128 BitLoc);
void getAllDUTsReadData(MultiSiteUnsignedLong128bit& data);
Unsigned128 getReadData(int site);
void getAllDUTsTestResultOnNode(MultiSiteUnsignedLong128bit& data);
void getAllDUTsTestResultOnNode(MultiSiteInt& data);
Unsigned128 getAllDUTsTestResultOnNode(int site);
```


New efuse Structure

- Simplify coding

Bit0	Bit1	Bit2	Bit3	Bit4	Bit5	Bit6	Bit7	Bit8	Bit9	Bit10	Bit11	Bit12	Bit13	Bit14	Bit15	Bit16	Bit17	Bit18	Bit19	Bit20	Bit21	Bit22	Bit23
data1	data1	data1	data1	data1	data1	data1	data1	data1	data1	data2	data2	data2	data2	data1	data1	data1	data1	data1	data2	data2	data2	data2	data2

Bit0	Bit1	Bit2	Bit3	Bit4	Bit5	Bit6	Bit7	Bit8	Bit9	Bit10	Bit11	Bit12	Bit13	Bit14	Bit15	Bit16	Bit17	Bit18	Bit19	Bit20	Bit21	Bit22	Bit23
data1	data1	data1	data1	data1	data1	data1	data1	data2	data2	data2	data2	data2	data2	data1	data1	data1	data1	data1	data1	data1	data2	data2	data2

If data bit location has changed, the reference calculate formula will changed accordingly

For data1, we need calculate address data as below:

Chip version = $((\text{data1} \& 0xff) | ((\text{data1} \& 0x7f00) \gg 14)) \& 0x1fc0ff$

Address0x0 = Address0x0 | Chip version >> 24

For data2, we need calculate address data as below:

Chip version = $(((\text{data2} \& 0x3f) \gg 8) | ((\text{data2} \& 0x1e0) \gg 21)) \& 0xe03f00$

Address0x0 = Address0x0 | Chip version >> 24

Complex coding

Optimizing

Complex coding work become simple **BitLoc value setting**. This BitLoc do not need to be concerned about node position in block level

```
void update_TestResult(int site, int data, int BitLoc);
```

data1/data2

Value

```
Data2:
- BitLoc = 000000000111100001111
Data1:
- BitLoc = 111111111000011110000
Data2:
- BitLoc = 0000000011111000000111
Data1:
- BitLoc = 11111111000000111111000
```

8 changes

2 changes

Safety and usability



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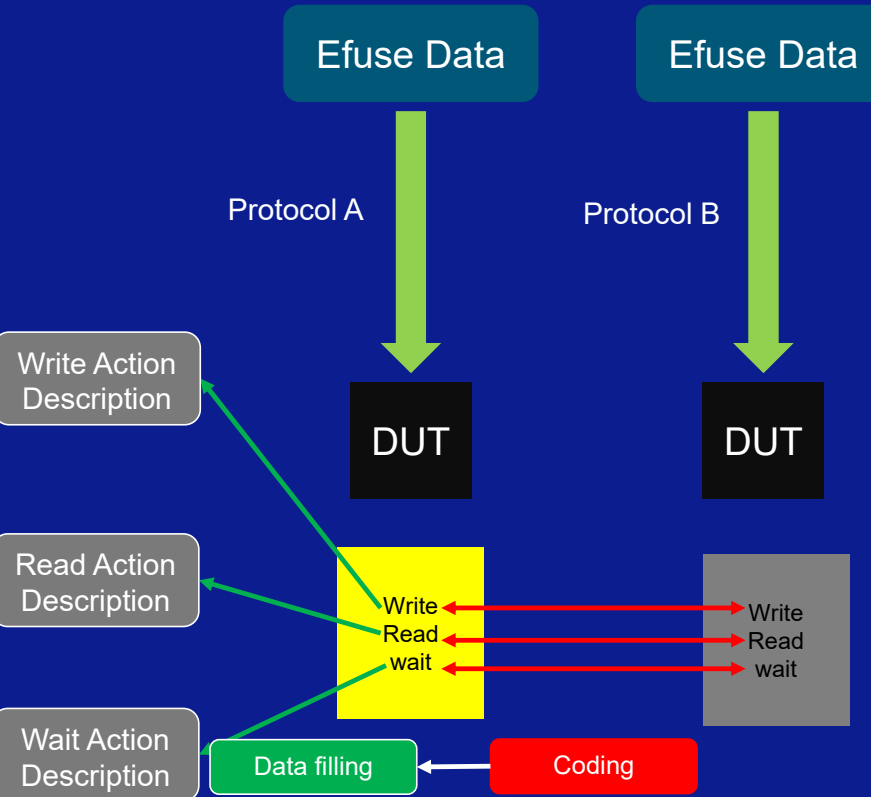
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New efuse Structure

Protocol Description Format

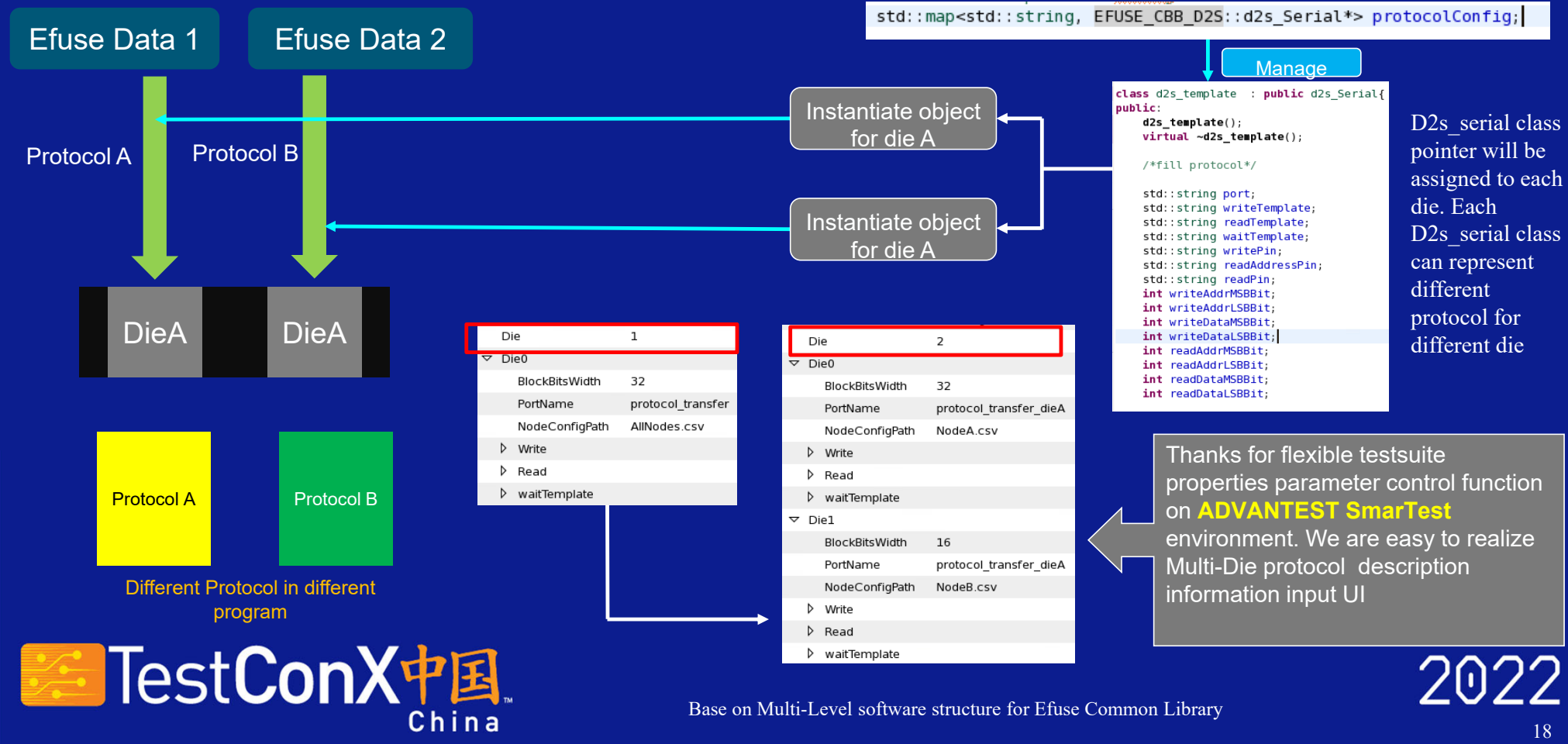
Test Method	EFUSE_CBB_tml.EfuseInit
Parameters	...
d2sMode	LearningMode
Die	1
Die0	
BlockBitsWidth	32
PortName	protocol_transfer
NodeConfigPath	AllNodes.csv
Write	
ADDR_PIN	address_pin
LabelName	protocol-pattern-write
ADDRLSB	128
ADDRMSB	120
DATALSB	150
DATAMSB	142
Read	
ADDR_PIN	address_pin
DATA_PIN	data_pin
LabelName	protocol-pattern-read
ADDRLSB	128
ADDRMSB	120
DATALSB	150
DATAMSB	142
waitTemplate	
LabelName	protocol-pattern-wait



Based on convenient operation interface of **ADVANTEST SmarTest** environment, we just need fill reference description data in testsuite properties. Then we using **D2S technology** to dynamic generate protocol vector and transfer to chip. (**D2S technology** is protocol software solution of **ADVANTEST SmarTest**, it support various serial/parallel protocol pattern generate,)

New efuse Structure

- MultiDie Protocol Management



Summary

*Implement Environment:
ADVANTEST SmarTest on V93000 platform*

Dgydqwdjh=

41 P dnh#surjudp #ghyharsp hqwtz run#fkdqjh#wr#fvy#nglwz klh#hixvh#G dwd#Orfdwlrq#
Fkdqjh#

51 Xsgdwh#G dwd#Surshw|#z lkrxw#hidfwrufedvlf#g dwd#wuxfwuh

61 Vlp sdi|#surwfrfnddjh#z lkrxw#hwvop hwkrg#p rgli|bjj#

71 Frp sdwedh#P xovlG lh#surwfrfnddjh#surjudp



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